U.S. Department of Commerce, Patent and Trademark			Atty. Docket No.			Application No.	
INFORMATION DISCLOSURE STATEMENT BY			SNDK.301US0			10/665,685	
APPLICANT			Applicant(s)			Conf. No.	
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*EXAMINER:	Initial if reference considered conformance and not considered	ed, whether or not dered. Include or	ot citation is in conformance	ce with MPI	EP 609; Draw lation to applica	ine through		